Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/750,355	MATHIEU ET AL.
Examiner	Art Unit
Edwin A. León	2833

	SEAR	CHED	
Class	Subclass	Date	Examiner
439	66	3/11/2006	EAL
	862		
	81-83		
V	515	V	V
upla	seach	101105	BUC
gright	slarch	4/26/06	PAL
			

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
•		ļ		
	}			
•				
		ļ		
•				
		<u>'</u>		
	:	1		
•	:			
•				